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FORM PTO-1449 (Modified) LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT(S) INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)	ATTN. DOCKET NO.	SERIAL NO.
	10031180-1	10/692.772
	APPLICANT	
	Mirkarimi, et al	
	FILING DATE	GROUP ART UNIT
	10/24/2003	1765

REFERENCE DESIGNATION		U.S. PATENT DOCUMENTS					
EXAMR INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	Subclass	Filing Date if Appropriate
LV	A1	5,624,529	4/29/1997	Dry Etching Method for Compound Semiconductors			
LV	A2	2003/066817	4/10/2003	Tanabe, et al Dry Etching Method and Apparatus-			
	A3						

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

LV	C1	Kim DW, et al - "A Study of GaN Etching Characteristics Using HBr-Based Inductively Coupled Plasmas" Solid State Electronics, Elsevier Science Publishers, Barking, GB
LV	C2	Pearson SJ, et al - "Dry Etching Characteristics of III-V Semiconductors in Microwave BCL3 Discharges" Plasma Chemistry and Plasma Processing, Plenum Press, New York, US - vol. 13, no. 2, June 1, 1993
LV	C3	Lee, et al - "Reactive Ion Etching of Vertical GaN Mesas by the Addition of Cl14 to BC13/H2/Ar Inductively Coupled Plasma" - Semiconductor Science and Technology, 10P, Bristol, GB. vol. 16, no. 6, June 2001
LV	C4	Langer JP, et al - "Electron Cyclotron Resonance Plasma Etching of GaSb in C12/BC13/CH4/Ar/H2 at Room Temperature" Journal of Vacuum Science & Technology B: Microelectronics Processing and Phenomena, American Vacuum Society, New York, NY, US - vol. 21, no. 4, July 2003.
	C5	

EXAMINER:	/Lan Vinh/	DATE CONSIDERED:	06/30/2006
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and <i>not</i> considered. Include copy of this form with next communication to Applicant(s).			